Foreword

Welcome to VTS 2009, the twenty-seventh in a series of annual symposia that focus on innovation in the field of testing of integrated circuits and systems.

The core of VTS 2009, the three day technical program, responds to the many trends and challenges in the semiconductor design and manufacturing industries with papers covering a diverse and seminal set of topics including, Fault Models, Transistor Aging and Power Supply Noise, Signal Integrity, Robust Design and Fault Tolerance, Radiation Test, Delay Fault Testing, Analog Test and Calibration, BIST, Microprocessor Test, Verification, Test Compaction, Debug, Diagnosis, Yield, Emergent Technology and Security.

In addition to the three-day technical program, VTS 2009 features several special sessions including several panels addressing various hot topics, two new topic speakers, and two student activity sessions. VTS 2009 continue the tradition of featuring the Innovative Practices track. The sessions that make up this track highlight cutting-edge challenges faced by test practitioners, and innovative solutions employed to address them. This year the Workshop on Test of Wireless Circuits and Systems will take place in conjunction with VTS for the second year.

Two tutorials are offered by the TTTC Tutorials & Education Group through the Test Technology Education Program (TTEP). This year the tutorials cover the exciting topics of Statistical Testing and Silicon Debug and Diagnosis. The tutorials provide opportunities for design and test professionals to update their knowledge base in test, and earn official IEEE TTTC accreditation.

The social program at VTS provides an opportunity for informal technical discussions among participants. Santa Cruz, with its beaches and mountains, provides a very attractive backdrop for all VTS 2009 activities.

VTS is the result of the work of many dedicated volunteers: the reviewers, the best paper award judges, the Program Committee, the Organizing Committee, and the Steering Committee. We wholeheartedly thank them all. We also wish to thank all the authors who submitted their works to VTS 2009, and the program participants for their contribution at the symposium. We thank the IEEE Computer Society Test Technology Technical Council for its continued sponsorship and support. Finally, we thank the Corporate Supporters of VTS 2009.

We hope that you will find VTS 2009 enlightening, thought-provoking, rewarding, and enjoyable. I wish you all a fun-filled and productive week in the Santa Cruz area and hope that you will keep making VTS a success by actively participating in it, assisting in its organization, and letting us always know when we can do something better. Thank you all for coming.

General Chair
Magdy Abadir

Program Chair
Cecilia Metra